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Patent Application

Inventor(s): Fusao Ishii

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Examiner: C. Young

Title: METHODS FOR PATTERNING SUBSTRATES HAVING ARBITRARY AND
 UNEXPECTED DIMENSIONAL CHANGES

Form 1449

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
/CY/	A	6,559,924	05/06/03	Ina et al.	355	53	05/30/01
	B	6,529,262	03/04/03	Mei et al.	355	47	04/12/00
	C	6,312,134	11/06/01	Jain et al.	359	855	01/23/99
	D	5,652,645	07/29/97	Jain	355	53	07/24/95
	E	4,924,257	05/08/90	Jain	355	53	10/05/88
	F	5,285,236	02/08/94	Jain	355	53	09/30/92
	G	5,291,240	03/01/94	Jain	355	53	10/27/92
	H	5,710,619	01/20/98	Jain et al.	355	50	10/31/95
	I	5,721,606	02/24/98	Jain	355	53	09/07/95
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	K	5,894,350	04/13/99	Hsieh et al.	356	399	06/12/98
	L	6,251,550	06/26/01	Ishikawa	430	22	07/07/99
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	O	6,342,703	01/29/02	Koga et al.	250	548	10/20/99
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Examiner Initial	No.	Pub. No.	Pub. Date	Patentee	Class	Sub-class	Filing Date
/CY/	W	2003/0025979	02/06/03	Chan et al.	359	279	12/28/01
/CY/	X	2003/0025981	02/06/03	Ishikawa et al.	359	290	07/31/01

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	Y							

/Christopher Young/ (05/19/2007)

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	Z	
Examiner /Christopher Young/ (05/19/2007)	Date Considered	05/19/2007

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered.
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